

<b>Notice of References Cited</b>	Application/Control No. 10/593,188		Applicant(s)/Patent Under Reexamination MOLITON, RENAUD	
	Examiner PETER RADKOWSKI		Art Unit 2883	Page 1 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,050,946 A	09-1991	Hathaway et al.	385/33
*	B	US-5,574,580 A	11-1996	Ansley, David A.	349/5
*	C	US-5,889,567 A	03-1999	Swanson et al.	349/62
*	D	US-6,057,966 A	05-2000	Carroll et al.	359/630
*	E	US-6,125,228 A	09-2000	Gong, Qian	385/146
*	F	US-6,222,677 B1	04-2001	Budd et al.	359/630
*	G	US-6,243,149 B1	06-2001	Swanson et al.	349/62
*	H	US-6,259,512 B1	07-2001	Mizouchi, Satoru	355/67
*	I	US-2001/0017604 A1	08-2001	JACOBSEN et al.	345/27
*	J	US-2001/0043166 A1	11-2001	JACOBSEN et al.	345/27
*	K	US-2001/0048493 A1	12-2001	Swanson et al.	349/62
*	L	US-6,331,916 B1	12-2001	Mukawa, Hiroshi	359/630
*	M	US-6,349,004 B1	02-2002	Fischer et al.	359/708

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No. 10/593,188	Applicant(s)/Patent Under Reexamination MOLITON, RENAUD	
		Examiner PETER RADKOWSKI	Art Unit 2883	Page 2 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,392,742 B1	05-2002	Tsuji, Toshihiko	355/67
*	B	US-2003/0030597 A1	02-2003	Geist, Richard Edwin	345/8
*	C	US-6,542,179 B1	04-2003	Kurtz et al.	348/97
*	D	US-2003/0184868 A1	10-2003	Geist, Richard Edwin	359/630
*	E	US-6,671,100 B1	12-2003	McRuer, Robert	359/630
*	F	US-6,771,423 B2	08-2004	Geist, Richard Edwin	359/630
*	G	US-6,819,493 B2	11-2004	Mizouchi, Satoru	359/619
*	H	US-2005/0063063 A1	03-2005	Ashdown, Ian	359/599
*	I	US-6,871,982 B2	03-2005	Holman et al.	362/331
*	J	US-2005/0078378 A1	04-2005	Geist, Richard Edwin	359/630
*	K	US-2005/0136200 A1	06-2005	Durell et al.	428/035.7
*	L	US-2006/0119951 A1	06-2006	McGuire, James P. JR.	359/630
*	M	US-7,145,726 B2	12-2006	Geist, Richard Edwin	359/630

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

**Notice of References Cited**

Application/Control No.

10/593,188

Applicant(s)/Patent Under  
Reexamination  
MOLITON, RENAUD

Examiner

PETER RADKOWSKI

Art Unit

2883

Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,206,133 B2	04-2007	Cassarly et al.	359/630
*	B	US-2007/0123769 A1	05-2007	Fuller et al.	600/405
*	C	US-7,230,766 B2	06-2007	Rogers, John R.	359/630
*	D	US-2007/0252954 A1	11-2007	McGuire et al.	353/020
*	E	US-2005/0093757	05-2005	Kiernan et al.	343/781.0CA
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.